

## General Description

The MY4446A uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

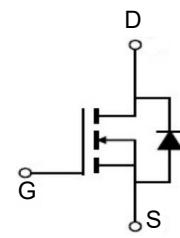
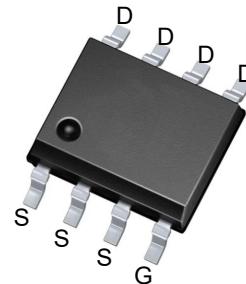


: YUh fYg

$X_{FUU}$	30	X
$I_F$	8	C
$T_{FUQP+CVXI U? 10X_+}$	19	o á
$T_{FUQP+CVXI U? 4.5X_+}$	24	o á

## Application

- Battery Protection
- Š[ æ Á, á&@
- Wj ä CII^] cæ|^Á[ , ^|Á^] ]^



## DUM\_U[Y A Ur\_]b[ UbX CfXYf]b[ -bZfa U]cb

DfcXi Wi-B	DUM_	A Ur_]b[	E lmfd7 G_L
MY4446A	ÜÜÜÜ	NULL	HEEE

5 Vgc`i H`AU Jai a 'FU[b[ g'fH, 18) °C unless otherwise noted)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	30	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_D @ T_A = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	8	A
$I_D @ T_A = 70^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	5.8	A
$I_{DM}$	Pulsed Drain Current <sup>2</sup>	30	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	20	mJ
$I_{AS}$	Avalanche Current	22	A
$P_D @ T_A = 25^\circ C$	Total Power Dissipation <sup>4</sup>	4.5	W
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C
$R_{\theta JA}$	Thermal Resistance Junction-ambient <sup>1</sup>	50	°C/W
$R_{\theta JC}$	Thermal Resistance Junction-Case <sup>1</sup>	30	°C/W

**Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)**

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	30	33	---	V
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	BVDSS Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =1mA	---	0.027	---	V/°C
R <sub>DSON</sub>	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V , I <sub>D</sub> =10A	---	19	28	mΩ
		V <sub>GS</sub> =4.5V , I <sub>D</sub> =8A	---	24	40	
V <sub>GS(th)</sub>	Gate Threshold Voltage		1.0	1.5	2.4	V
ΔV <sub>GS(th)</sub>	V <sub>GS(th)</sub> Temperature Coefficient	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	---	-5.8	---	mV/°C
I <sub>DS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C	---	---	1	uA
		V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C	---	---	10	
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V	---	---	±100	nA
g <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> =5V , I <sub>D</sub> =10A	---	5.8	---	S
R <sub>g</sub>	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz	---	2.2	3.8	
Q <sub>g</sub>	Total Gate Charge (4.5V)	V <sub>DS</sub> =15V , V <sub>GS</sub> =4.5V , I <sub>D</sub> =10A	---	12.6	17.6	nC
Q <sub>gs</sub>	Gate-Source Charge		---	4.2	5.9	
Q <sub>gd</sub>	Gate-Drain Charge		---	5.1	7.1	
T <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> =15V , V <sub>GS</sub> =10V , R <sub>G</sub> =3.3 I <sub>D</sub> =10A	---	6.2	12.4	ns
T <sub>r</sub>	Rise Time		---	59	106	
T <sub>d(off)</sub>	Turn-Off Delay Time		---	27.6	55	
T <sub>f</sub>	Fall Time		---	8.4	16.8	
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , f=1MHz	---	960	---	pF
C <sub>oss</sub>	Output Capacitance		---	139	---	
C <sub>rss</sub>	Reverse Transfer Capacitance		---	87	---	
I <sub>s</sub>	Continuous Source Current <sup>1,5</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current	---	---	10.3	A
I <sub>sM</sub>	Pulsed Source Current <sup>2,5</sup>		---	---	42	A
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>s</sub> =1A , T <sub>J</sub> =25°C	---	---	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> =10A, dI/dt=100A/μs, T <sub>J</sub> =25°C	---	12.5	---	nS
Q <sub>rr</sub>	Reverse Recovery Charge		---	5	---	nC

Note :

- 1 .The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3 .The EAS data shows Max. rating . The test condition is V<sub>DD</sub>=25V,V<sub>GS</sub>=10V,L=0.1mH,I<sub>AS</sub>=35A
- 4.The power dissipation is limited by 150°C junction temperature 5.The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub> , in real applications , should be limited by total power dissipation.

### Typical Characteristics

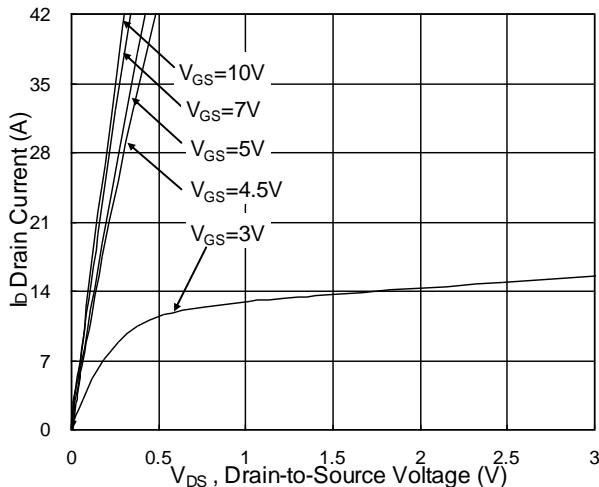


Fig.1 Typical Output Characteristics

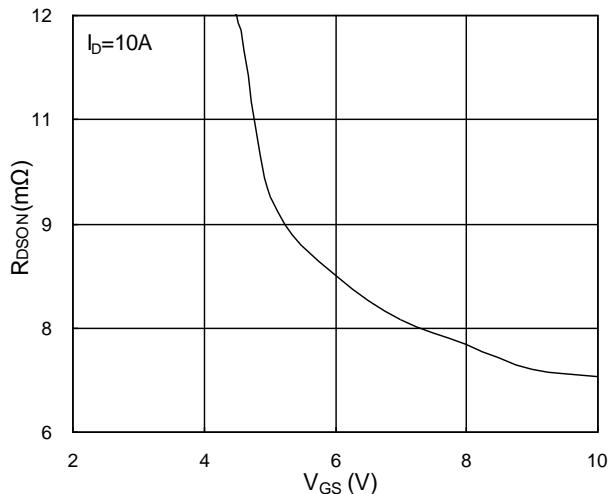


Fig.2 On-Resistance vs. Gate-Source

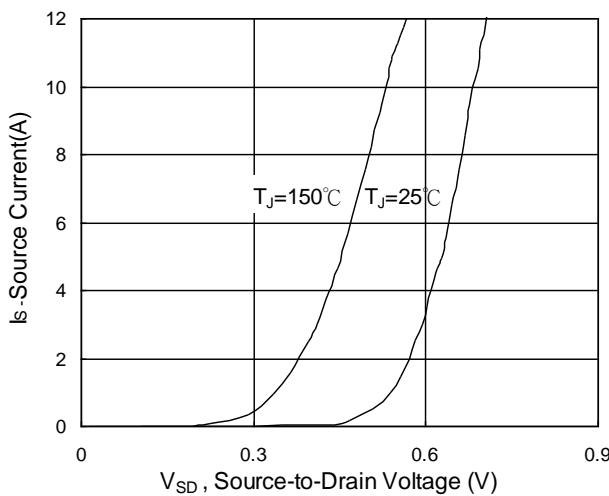


Fig.3 Forward Characteristics of reverse

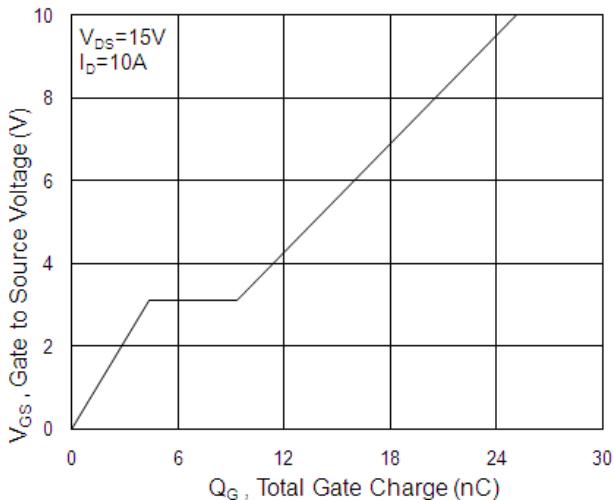
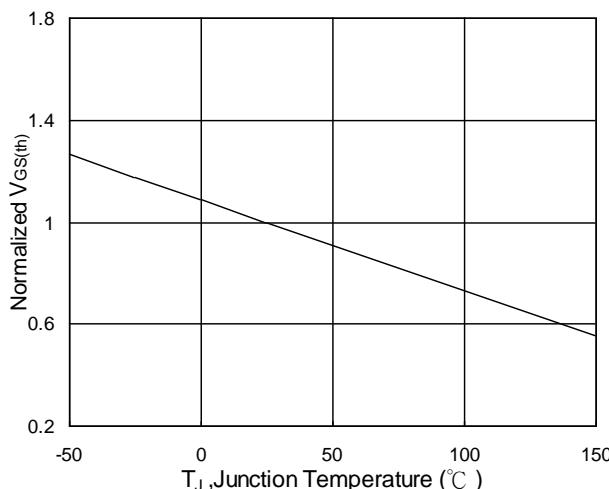
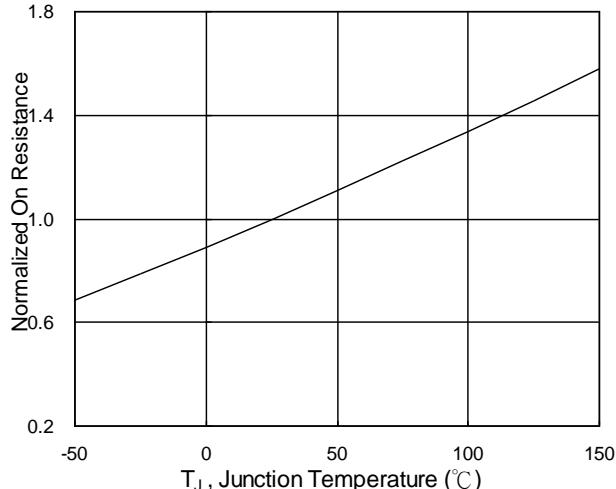


Fig.4 Gate-Charge Characteristics

Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$ Fig.6 Normalized  $R_{DS(on)}$  vs.  $T_J$

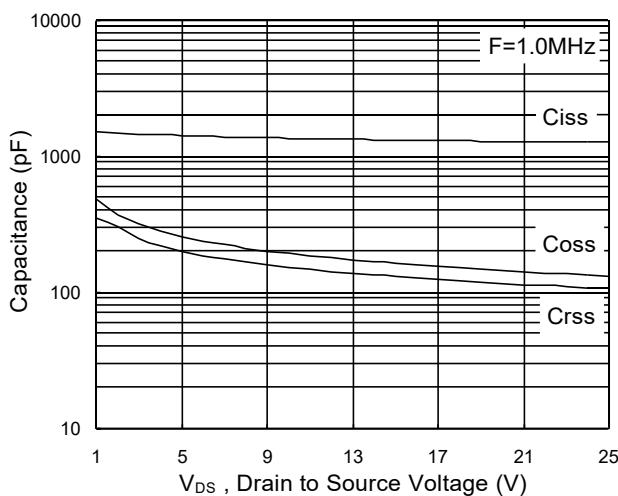


Fig.7 Capacitance

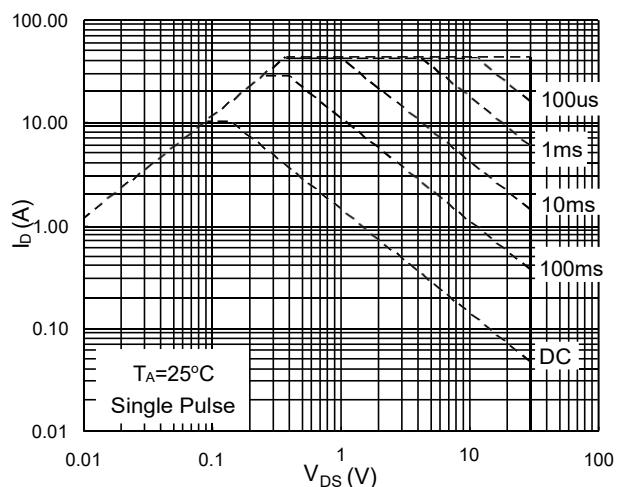


Fig.8 Safe Operating Area

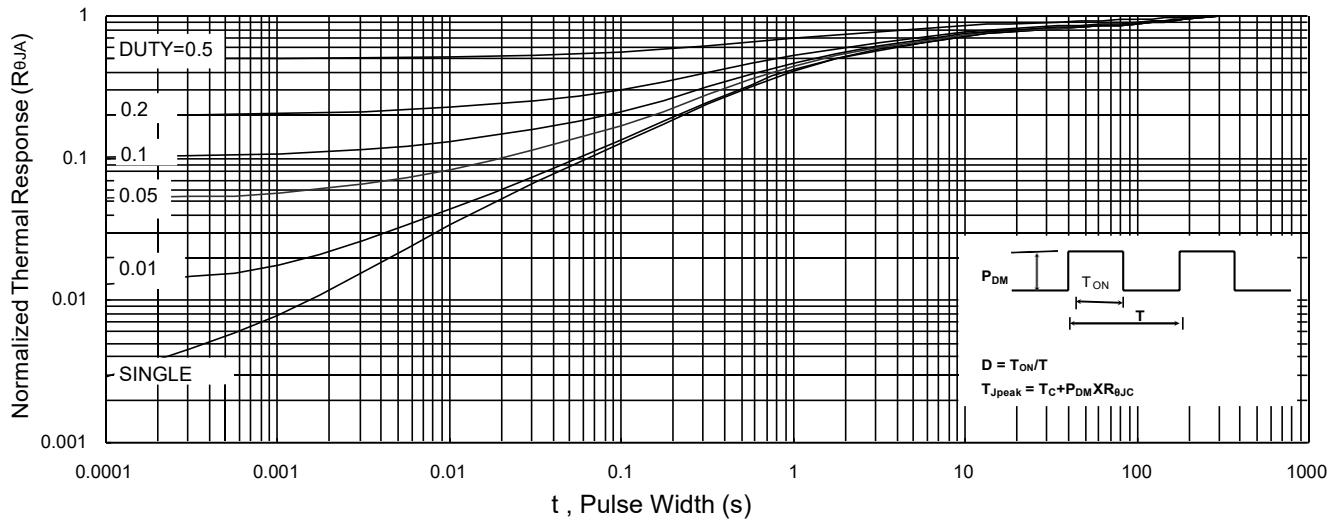


Fig.9 Normalized Maximum Transient Thermal Impedance

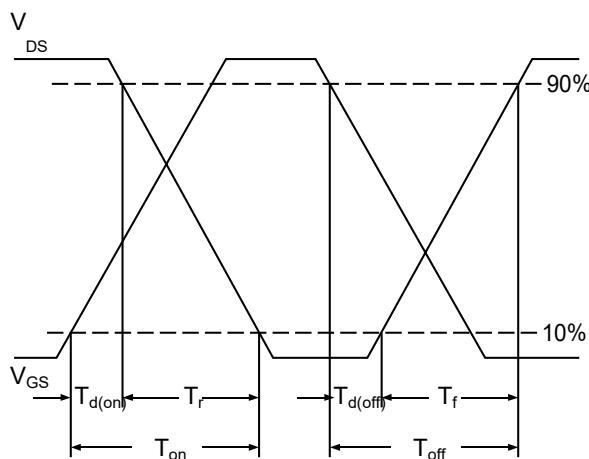


Fig.10 Switching Time Waveform

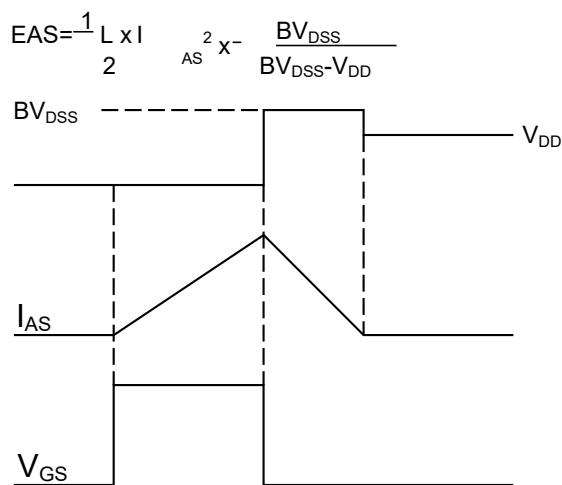
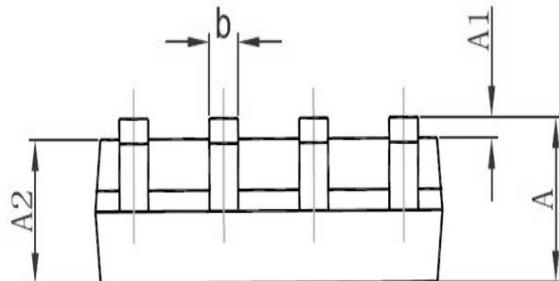
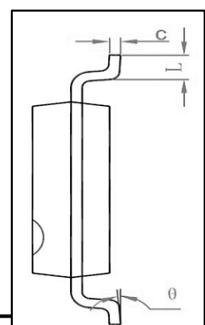
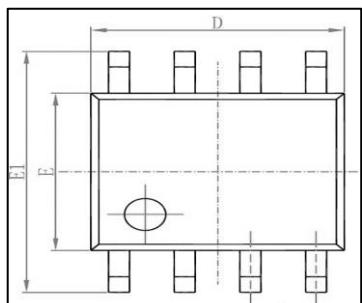
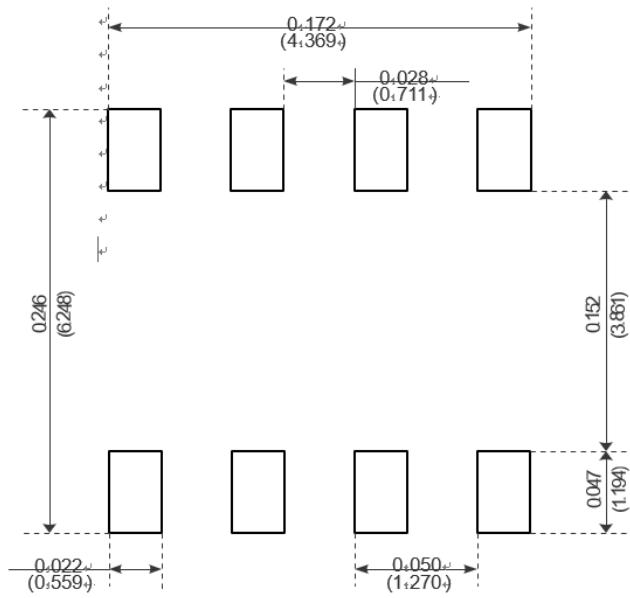


Fig.11 Unclamped Inductive Switching Waveform

### Package Mechanical Data-SOP-8



Symbol	Dimensions in Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	1.350	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0.510	0.013	0.020
c	0.170	0.250	0.006	0.010
D	4.700	5.100	0.185	0.200
E	3.800	4.000	0.150	0.157
E1	5.800	6.200	0.228	0.244
e	1.270 (BSC)		0.050 (BSC)	
L	0.400	1.270	0.016	0.050
$\theta$	0°	8°	0°	8°



Recommended Minimum Pads